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From models to mechanisms: defects and charge trapping in amorphous silicon nitride

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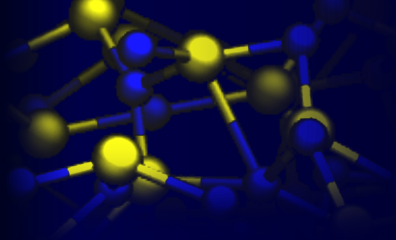
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Defects and Charge Trapping in
Amorphous Silicon Nitride**



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L. Hückmann

